

Search Notes

Application/Control No.

09/669,854

Examiner

Quoc A. Tran

Applicant(s)/Patent under
Reexamination

IKEDA, IKUYO

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	764	7/9/2005	
358	1.15	7/9/2005	
345	629	7/9/2005	
Updated	Above	11/25/2005	
Upadted	Above	6/24/2006	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
715	527	6/24/2006	
715	863	6/24/2006	
358	1.15	6/24/2006	


**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	7/9/2005	
EAST (US-PAT, US-PGPUB) see Search Histoty Printout	7/9/2005	
NPL IEEE DataBase see Search History Printout	7/9/2005	
Updated Above	11/25/2005	
EAST (UAPAT, USPGPUB, EPO JPO, DERWENT, USOCR, IBM_TDB) See Search History Printout	6/24/2006	
ACM Digital library& STIC Search (see search Prinout)	6/24/2006	
Interference Search (EAST US- PGPUB) see search printout	6/24/2006	
Consulting Primary Examiner Jerome Grant II TC - 2625	6/22/2006	

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	09/669,854	IKEDA, IKUYO	
	Examiner	Art Unit	
	Quoc A. Tran	2176	

SEARCHED			
Class	Subclass	Date	Examiner
358	1.15	8/31/04	QJ
↓	474		
250	234		
382	194		
↓	289		
400	477	↓	↓
update above		2/19/05	QJ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
US. PAT	8/31/04	QJ
US. P & PUB	↓	↓
EPO	↓	↓
JPO	↓	↓
DERWENT	↓	↓
IBM-TDRS	↓	↓
update above	2/19/05	QJ

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